Correction


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Error in Figure

We noticed that Figure 1 in the original publication [1] has incorrect X-labels. The figure depicts a comparative analysis of various X-ray sources, and incorrect labels could potentially mislead interpretation. The authors state that the scientific conclusions are unaffected. This correction was approved by the Academic Editor. The original publication has also been updated.

Figure 1. (a) Peak brightness for different X-ray sources: The APS synchrotron in the USA, the BESY facility in Germany, ESRF in France, EU XFEL in Germany, the LCLS facility in the USA, FERMI in Italy, SACLA in Japan, the SPRING synchrotron facility in Japan, the HHG beamline at ELI Beamlines [10], the ELI Beamlines Gammatron beamline and all-optical Compton sources [19,29]. (b) Peak brightness of the laser plasma accelerator (LPA)-driven Betatron X-ray source at different laser facilities [30–38] and the expected brightness of the Betatron X-ray source at ELI Beamlines.

Reference


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